

BAFFI: a bit-accurate fault injector for improved dependability assessment of FPGA prototypes

Ilya Tuzov¹, David de Andrés², Juan-Carlos Ruiz², and Carles Hernández¹

¹DISCA, Universitat Politècnica de València, Campus de Vera s/n, 46022, Spain

²ITACA, Universitat Politècnica de València, Campus de Vera s/n, 46022, Spain

tuil@upv.es, ddandres@disca.upv.es, jcruizg@disca.upv.es, carherlu@upv.es

This paper will be made available after
the DATE conference 2023 presentation at 19 April 2023

This paper appears in the list of accepted papers of the DATE 2023 conference under the ID 793

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